

# Measuring multiple RTDs with a multiplexed ADC & intro to conversion latency

TI Precision Labs – ADCs

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Presented by Josh Brown

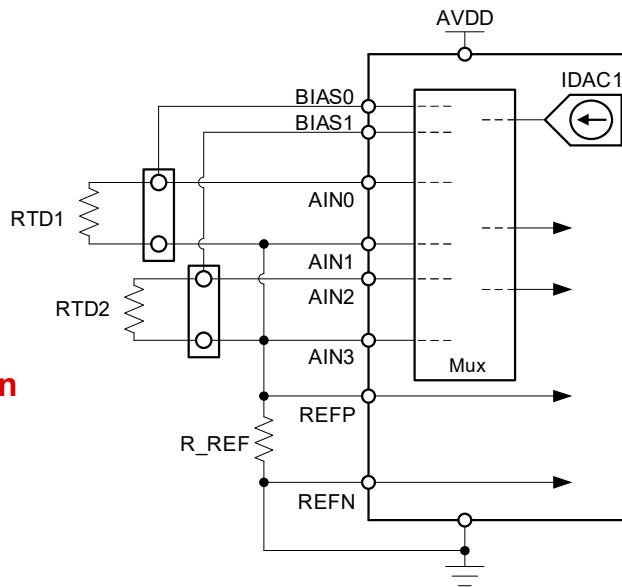
# Types of multi-RTD measurement systems

Same **wiring configuration** for all RTDs

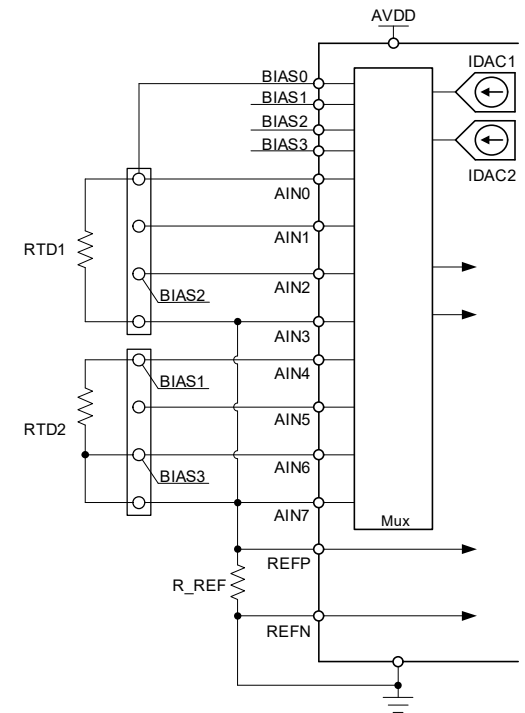
# of wires, not RTD type  
e.g. platinum, nickel, etc.

Different **wiring configuration** for all RTDs

- ✓ Simple to implement, fewer ADC channels required
- ✗ Measure one RTD wiring configuration e.g. 2-wire only



- ✓ Can measure 2-, 3-, or 4-wire RTDs with the same hardware
- ✗ Requires more inputs per RTD and potentially external jumpers

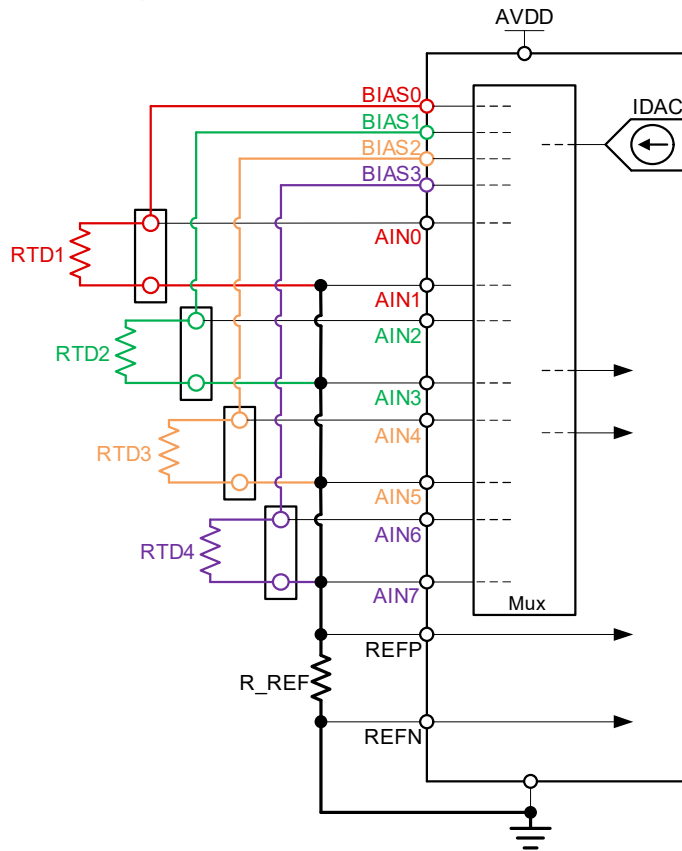


\*\*Discussed in **this** Precision Labs module\*\*

\*\*Discussed in a **separate** Precision Labs module\*\*

# Measuring multiple RTDs (same wiring config)

## Measuring 4x 2-wire RTDs (low-side R\_REF)

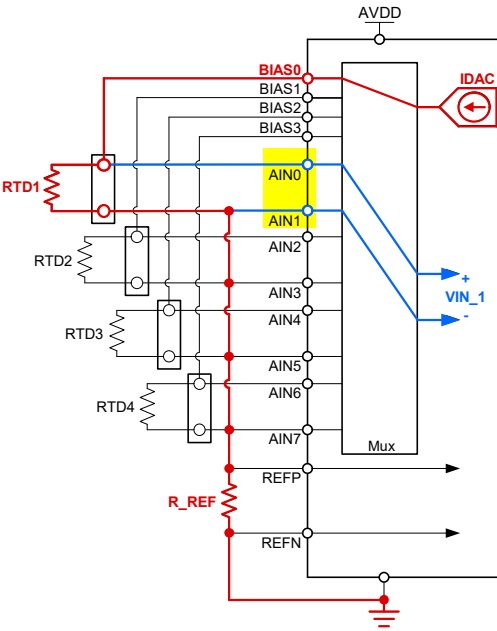


### System requirements:

- 2x analog inputs (AINx) per RTD
  - 1x IDAC & 1x output (BIASx) per RTD
  - 1x differential reference input (REFx) common to all RTDs
  - Common return current path through R\_REF
- ✓ Same ADC requirements for measuring multiple 4-wire RTDs (greater number of terminal block inputs)
- × More complicated for multiple 3-wire RTDs
- × More complicated for high-side R\_REF

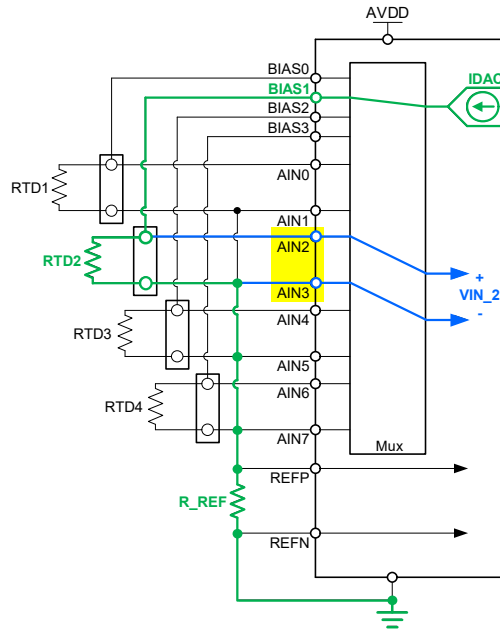
# Process for measuring multiple RTDs

## Measuring RTD1



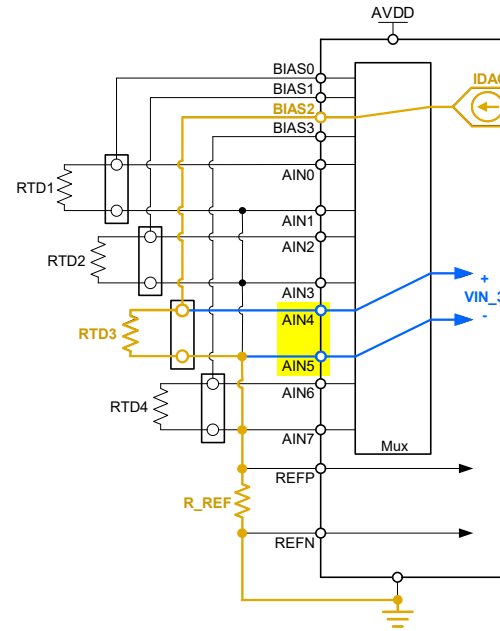
- Switch IDAC to BIAS0
- Switch MUX to AIN0 / AIN1
- Measure VIN<sub>1</sub>

## Measuring RTD2



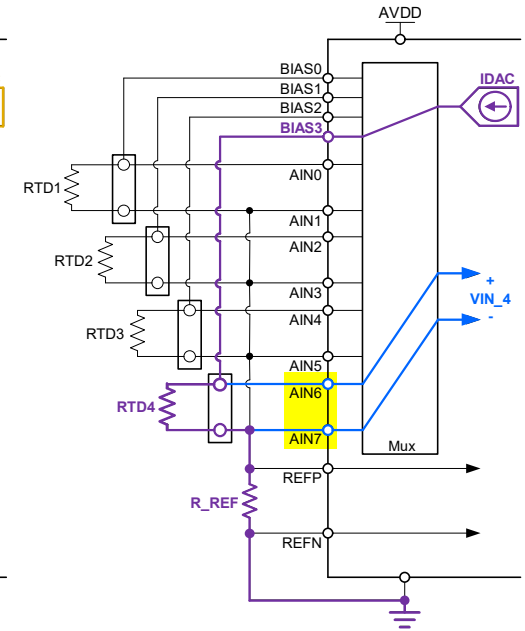
- Switch IDAC to BIAS1
- Switch MUX to AIN2 / AIN3
- Measure VIN<sub>2</sub>

## Measuring RTD3



- Switch IDAC to BIAS2
- Switch MUX to AIN4 / AIN5
- Measure VIN<sub>3</sub>

## Measuring RTD4

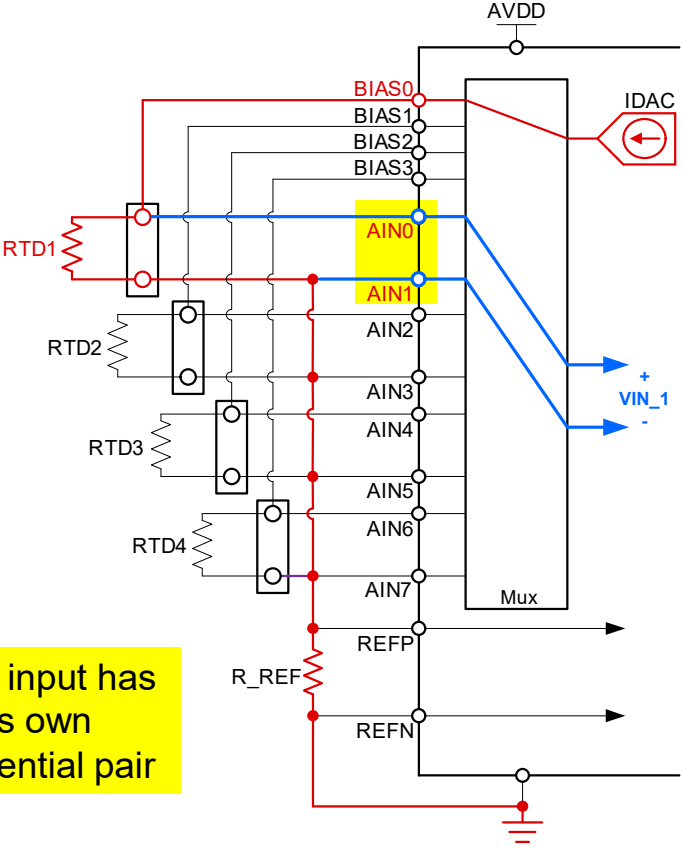


- Switch IDAC to BIAS3
- Switch MUX to AIN6 / AIN7
- Measure VIN<sub>4</sub>

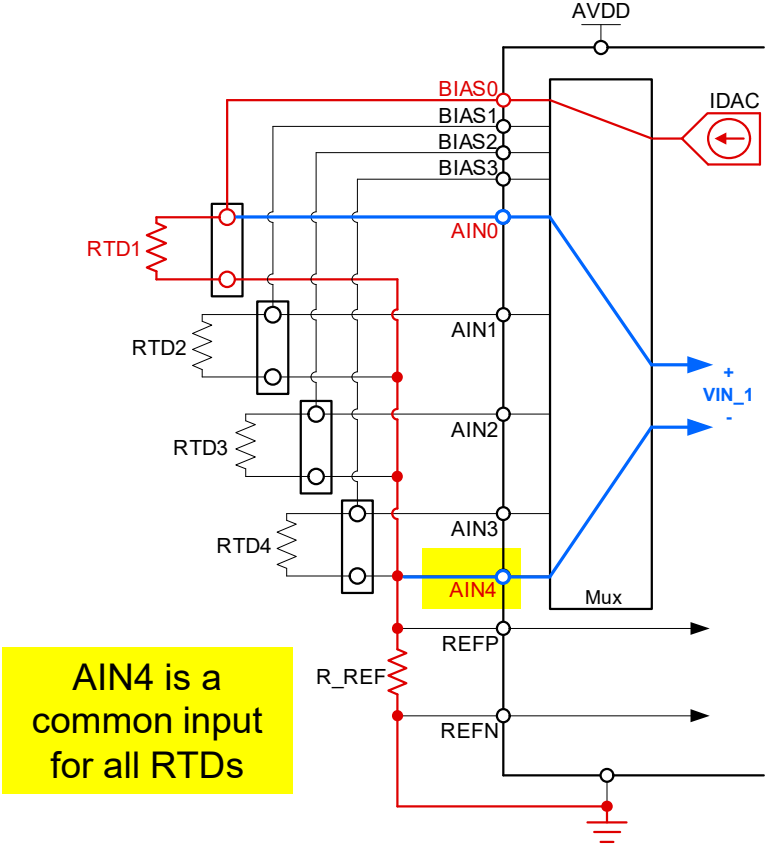
**\*\*Repeat process as needed\*\***

# Reducing the number of analog inputs

2x analog inputs per RTD

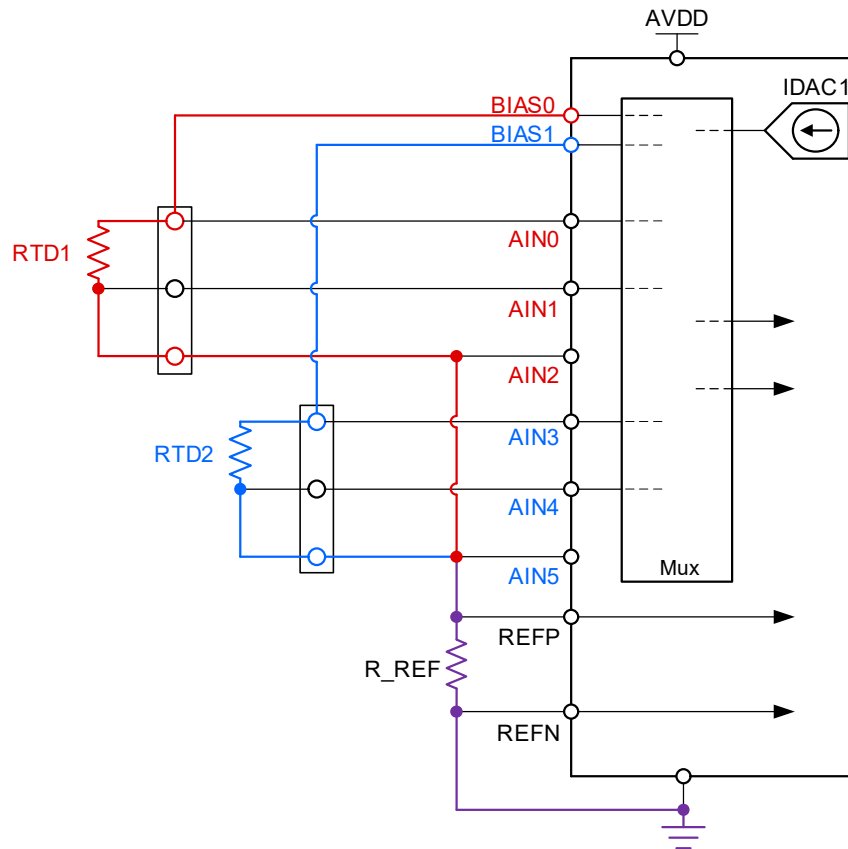


1x analog input per RTD + 1x common input



# Measuring multiple 3-wire RTDs using 1x IDAC

## Measuring 2x 3-wire RTDs using 1x IDAC (low-side R\_REF)

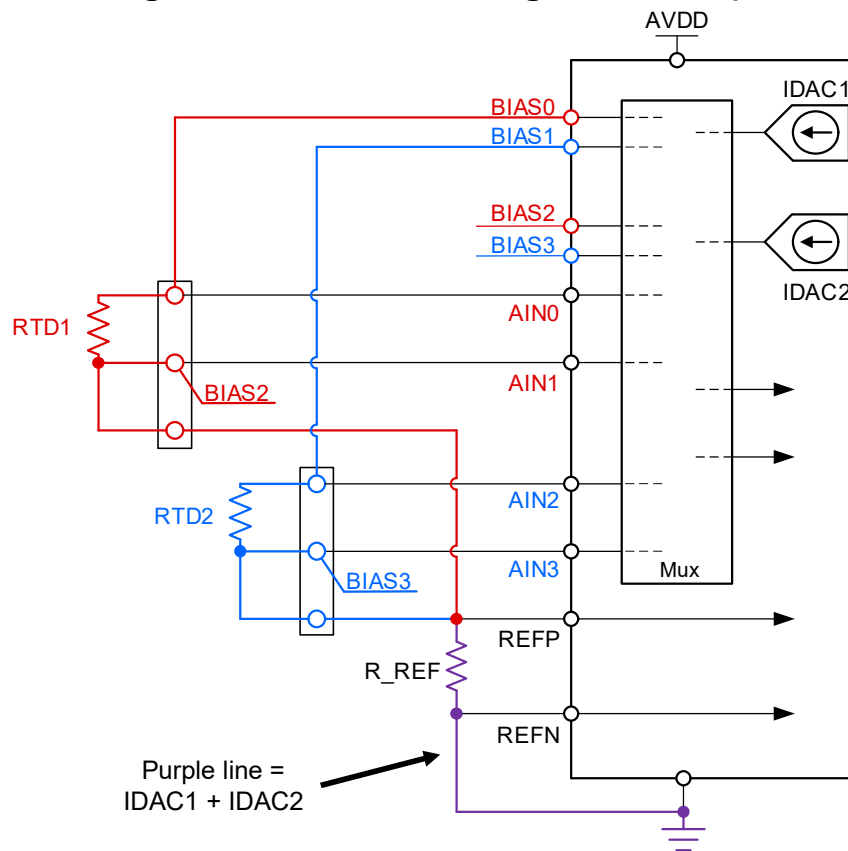


### System requirements:

- 3x analog inputs (AINx) per RTD
  - 1x IDAC & 1x output (BIASx) per RTD
  - 1x differential reference input (REFx) common to all RTDs
  - Common return current path through R\_REF
- ✓ Fewer IDAC outputs per RTD compared to 2x IDAC solution
  - ✓ No IDAC mismatch error
  - ✗ Two measurements per RTD increases conversion latency

# Measuring multiple 3-wire RTDs using 2x IDACs

## Measuring 2x 3-wire RTDs using 2x IDACs (low-side R\_REF)



### System requirements:

- 2x analog inputs (AINx) per RTD
- 1x IDAC & 2x outputs (BIASx) per RTD
- 1x differential reference input (REFx) common to all RTDs
- Common return current path through R\_REF

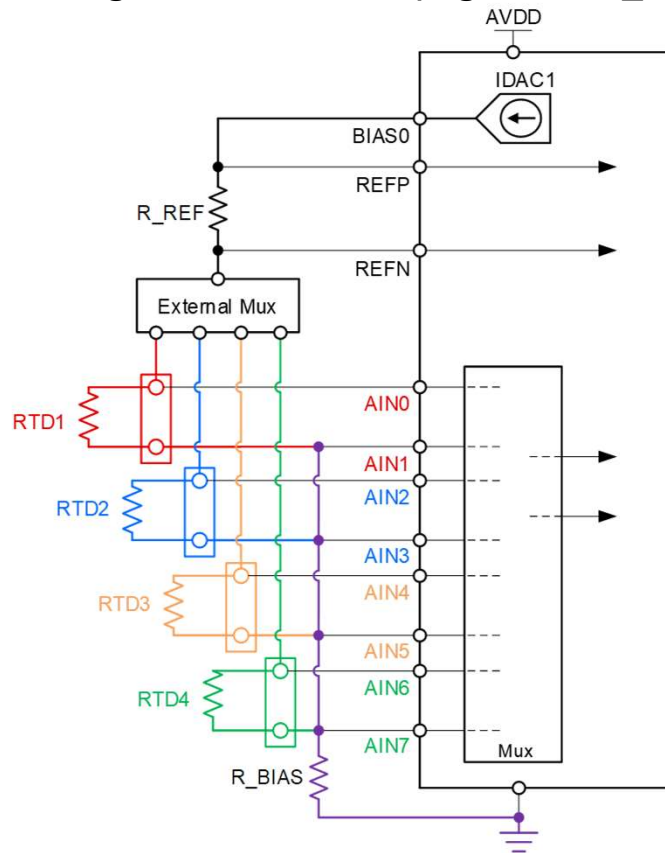
✓ **One conversion per RTD**

✗ **Additional IDAC output required compared to 1x IDAC solution**

✗ **Need to consider IDAC mismatch error**

# Measuring multiple RTDs with a high-side R\_REF

## Measuring 4x 2-wire RTDs (high-side R\_REF)



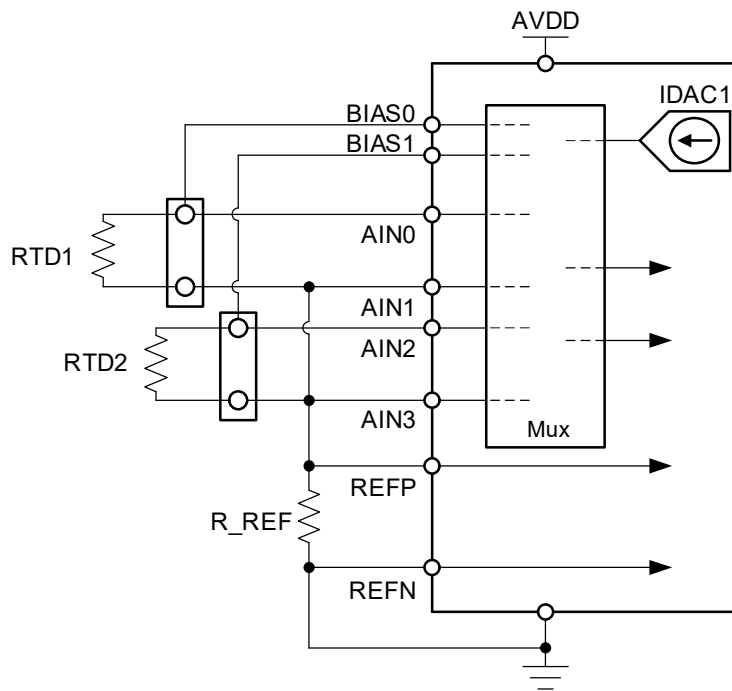
### System requirements:

- 2x analog inputs (AINx) per RTD
- 1x IDAC output (BIASx) common to all RTDs
- 1x differential reference input (REFx) common to all RTDs
- 1x external multiplexer to route the IDAC current to the correct RTD
- Common return current path through R\_BIAS
- ✓ Fewer IDAC outputs required compared to low-side R\_REF
- ✓ If applicable, ADC GPIOs can be used to control the external multiplexer
- ✗ External multiplexer(s) required



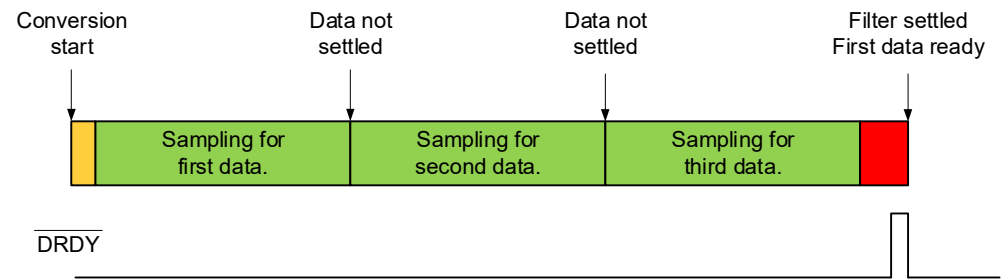
# Conversion latency

## Measuring multiple RTDs

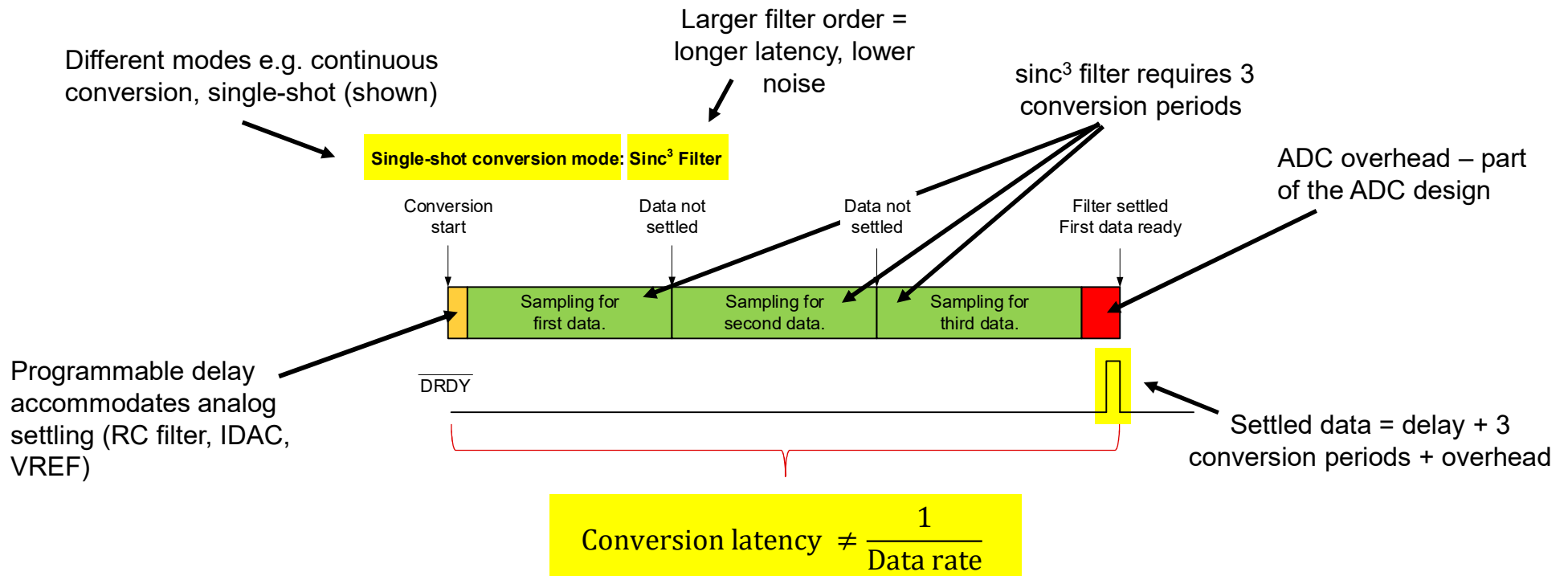


## ADS124S08 conversion latency

Single-shot conversion mode: Sinc<sup>3</sup> Filter



# Delta-sigma ADC conversion latency considerations



[For more detailed information, review TI's app note on conversion latency \(SBA535\)](#)

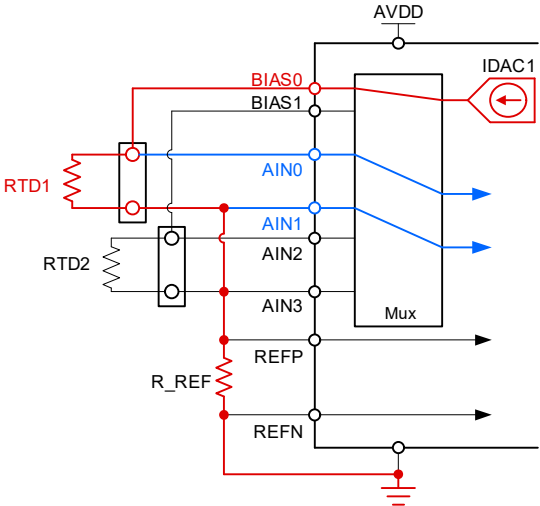
# Example: multiple RTD measurement cycle time

**Example parameters:**

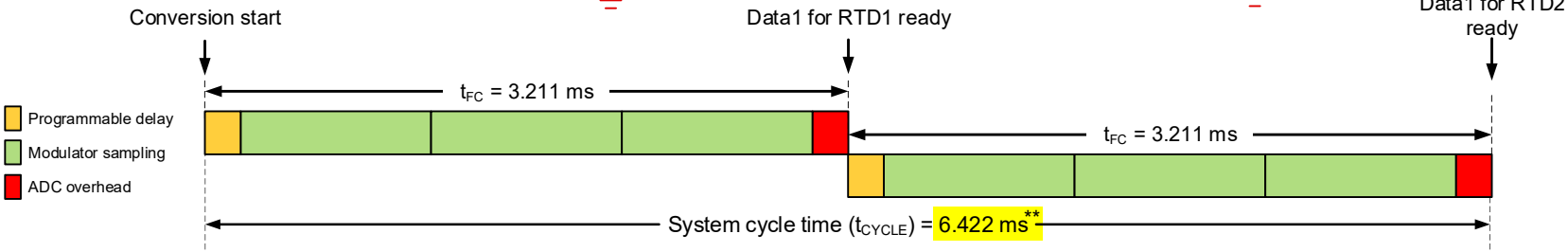
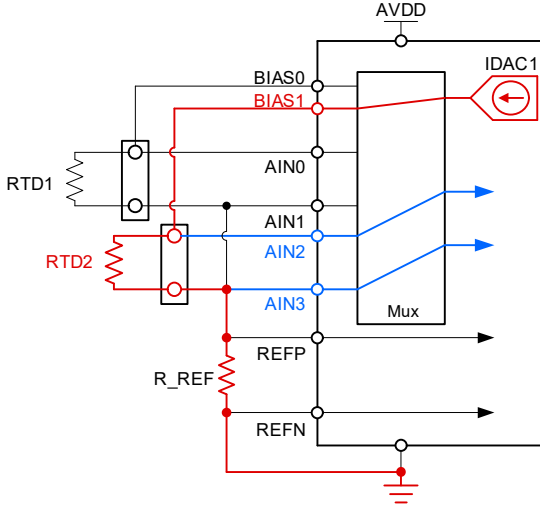
- ADS124S08
- 1 kSPS
- Sinc<sup>3</sup> filter
- Delay = 14\*t<sub>MOD</sub>



Measuring RTD1



Measuring RTD2



\*\*Ignores ADC communication time to change configuration

**Thanks for your time!  
Please try the quiz.**

## Quiz: Multiple RTDs & conversion latency

1. (True/False) Some ADCs used to measure RTD signals can require multiple conversion cycles for the signal to settle to an accurate value. This settling time is referred to as conversion latency.
  - a) True
  - b) False
  
2. (True/False) When switching multiplexer inputs, some additional delay may be required to account for analog settling. Some ADCs include a programmable delay for this purpose.
  - a) True
  - b) False

**Thanks for your time!**



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